


<b>Search Notes</b>  	<b>Application/Control No.</b>  09926007	<b>Applicant(s)/Patent Under Reexamination</b>  NISHIBE ET AL.
	<b>Examiner</b>  PHILIP C LEE	<b>Art Unit</b>  2152

### SEARCHED

Class	Subclass	Date	Examiner
709	219,228,229,203	2/14/08	/pl/
713	190,151,153	2/14/08	/pl/
705	59	2/14/08	/pl/
709	219,228,229,203	8/14/08	/pl/
713	190,151,153	8/14/08	/pl/
705	59	8/14/08	/pl/

### SEARCH NOTES

Search Notes	Date	Examiner
Consulted with SPE:Bunjoo Jaroenchonwanit regarding allowable subject matters	2/12/08	/pl/
Keywords search in EAST	2/14/08	/pl/
Inventor Named Search	2/11/08	/pl/
keywords search in 709/219,228,229,203;713/190;713/151,153,190;705/59;726/5 in EAST	2/14/08	/pl/
Google Search	2/14/08	/pl/
ACM/IEEE Search	2/14/08	/pl/
Search 709/219,228,229,203;713/190;713/151,153,190;705/59;726/5 in PG Pub	2/14/08	/pl/
update keywords search in EAST	8/14/08	/pl/
update keywords search in 709/219,228,229,203;713/151,153,190;705/59;726/5 in EAST	8/14/08	/pl/
update Google search	8/14/08	/pl/
update ACM/IEEE search	8/14/08	/pl/
Search 709/219,228,229,203;713/190;713/151,153,190;705/59;726/5 in PG Pub	8/14/08	/pl/

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
709	219,228,229,203	2/14/08	/pl/
713	190,151,153	2/14/08	/pl/
705	59	2/14/08	/pl/
726	5	2/14/08	/pl/
709	219,228,229,203	8/14/08	/pl/

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# INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
713	190,151,153	8/14/08	/pl/
705	56	8/14/08	/pl/
726	5	8/14/08	/pl/

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